

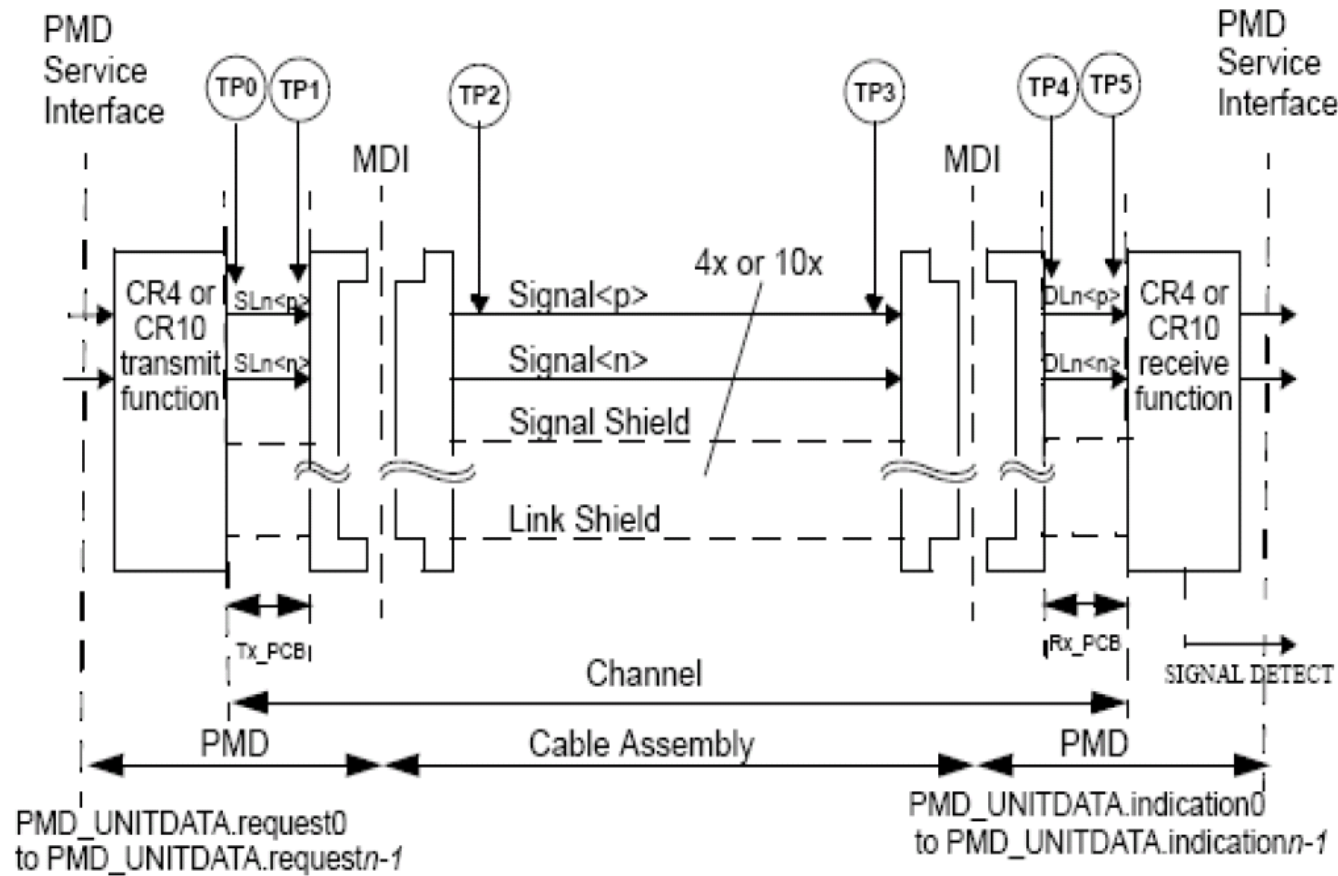
CR4 and CR10 TP2 Specifications

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Test Points for Clause 85



Existing Informative TP2 Specifications

Table 85-5—Transmitter characteristics'at TP2 summary

Parameter	Value	Units
Maximum total jitter ^a	0.36	UI p-to-p
minimum KR transmit waveform "v ₂ " ^b	267	mV
QSQ ^c	55.6	
Vertical eye opening ^d	340	mV p-to-p

^aMeasurement procedure is similar to TP0, with all TX lanes active and de-emphasis adjusted optimally.

^bThe test pattern for the transmitter output waveform is the square wave test pattern defined in 52.9.1.2, with a run of at least eight consecutive ones. Measurement procedure is similar to TP0, with same de-emphasis setting as total jitter measurement.

^cThe lane under test shall transmit square wave pattern defined in 52.9.1.2, with a run of at least eight consecutive ones, while other lanes shall transmit PRBS31. The value of the standard deviation of the sampled waveform at the center of the measurement window for v₂ shall be measured as m. QSQ is defined as (v₂/m); "20*log₁₀(QSQ)" can be interpreted as SNR in "dB".

^dInformative parameter; jitter is specified at BER 10⁻¹².

- Not sufficient to ensure signal measured will propagate successfully to TP5 and be recovered.

KR and CR

- Moving TP0 Specs to TP2
 - SDD21 effective is measurable, ILTP2(f)
 - Many Tx specification are not directly observable too much of the Channel in the way
 - Apply equalizations to TP2 measured data to recover signal back to a perhaps fictitious point RP0, before any loss or dispersion due to the IC, package, PCB, connector, or the test fixture.
 - Measure the waveform, RJ and DJ at RP0

TP2 Specifications 1/3

- Table 85.5. Transmitter characteristics at TP2

Parameter	Units	Value		Notes
		Max	Min	
Signaling Speed	GBd	10.3135	10.3115	
Unit Interval	ps			Place holder
Common Mode Voltage	V	1.9	0	
Differential Output Return Loss	dB	See Equation 85.XX		
Peak to peak Amplitude	V	1200		72.7.1.4 (b)
Transmitted waveform				72.7.1.10 (b)

TP2 Specifications 2/3

Parameter	Units	Value		Notes
		Max	Min	
ILTP2 AN0	dB	1.6	-2.0	(a)
ILTP2 AN1	dB	2.5	1.25	(a) Further refinement
ILTP2 AN2	dB	1.0	0	(a) Further refinement
ILTP2 AN4	dB	3.5	1.0	(a) Further refinement
ILTP2 AN1+AN2	dB	3	1.5	(a) Further refinement
ILDTP2		See Eq. 85.y		(a) Place holder
DJ	UI	0.15		(b)
DCD	UI	0.035		(b)
RJ	UI	0.25		(b)
TJ	UI	.36		(b)
Return Loss	dB	Eq 72.5		Section 72.4
Propagated Noise Short	mVrms	$6 \cdot 10E(AN0/20)$		(e)
Propagated Noise Long	mVrms	$0.6 \cdot 10E(AN0/20)$		(f)

TP2 Specifications 3/3

- a) $ILTP2 = 20 * (a0 + a1 * \sqrt{f} + a2 * f + a4 * f^2) / \log_{10}$ See Section 85.XXX

$$ANn = 20 * an * (datarate/2)^{(n/2)} / \log(10)$$

- b) Measured with effect of ILiTP2 loss mathematically removed from the signal at TP2 using a software FIR filter that is no more than 6UI long.
- c) Jitter is specified at BER 10e-12
- d) Duty Cycle Distortion is considered part of the deterministic jitter distribution.
- e) Noise data filtered by the short cable transfer function See Section 85.YYY
- f) Same data as in note e but with the filter being the long cable.

Method for ILTP2

(Table 85-5 note (a) Procedure

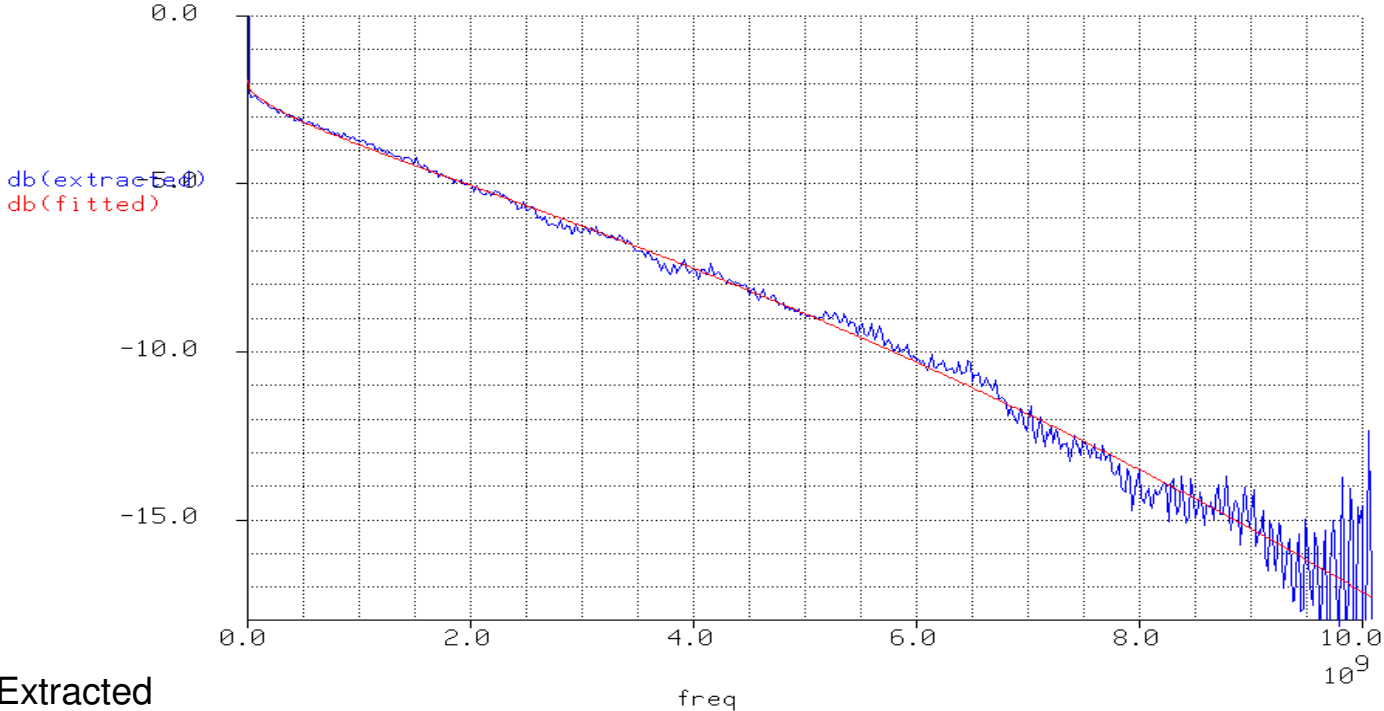
- Let IN be the ideal 1 Vpp PRBS signal
- Let OUT be the capture TP2 signal
- FIN and FOUT are the complex DFT's of IN and OUT respectively
- XFER=complex ratio FOUT/FIN
- ILiTP2measured=-dB of XFER
- ILTP2 is the LMS fit to ILiTP2 , weighted by the SINC² to remove effects of null at fbaud
 - $ILTP2 = 20 * (a_0 + a_1 * \sqrt{f} + a_2 * f + a_4 * f^2) / \log 10$

Method for Propagated Noise

Table 85-5 notes (e and f)

- Measured with transmitter sending through TP2 a PRBS9, and all other transmitters terminated beyond TP2 sending PRBS31. sample at least 1000000 consecutive bits, sampling at least 3 times the data rate. For each bit, select the sample closest to the optimum sampling point for data recovery. For each of the 511 bits in the PRBS pattern, find the average of the near optimum samples. Filter the noise either
 - a) The frequency domain by performing a DFT on the noise samples and multiplying the loss function defined in equation 85.x1 for short channel and equation 85.x2 for the long channel
 - b) The time domain by convolving the samples with the FIR filter samples given in Table 85.yyy for the short channel or the long channel.

Raw and Fitted Test Channel 1



Loss Breakdown (dB)

PCB	2
Conn.	0.5
HCB	1
Package 1(model)	
Tr/Tf	1.67
Cabling	0.88*

Total	7.05

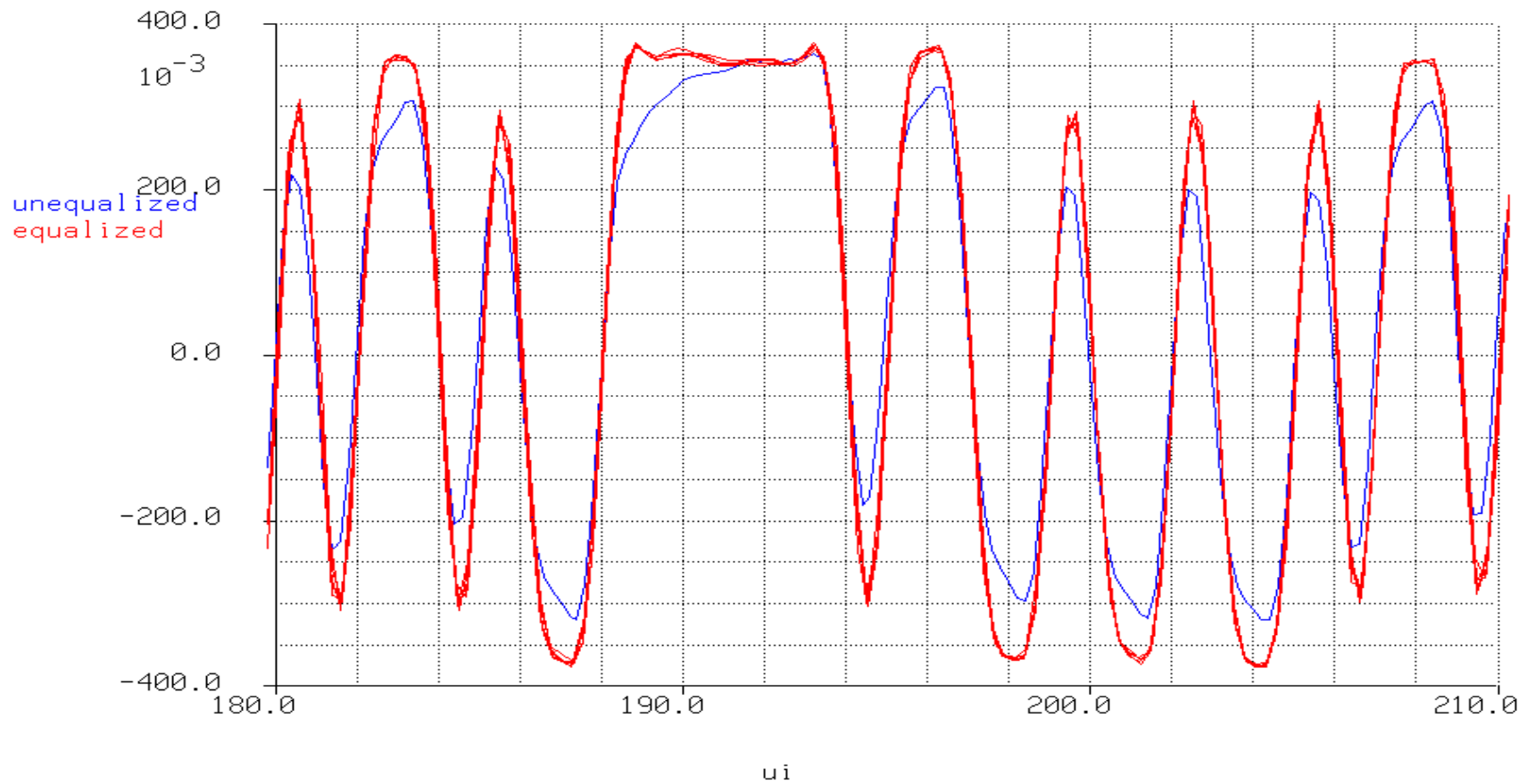
Extracted
 DCD : 7mUI p-p
 other PJ : 26mUI p-p
 RJ : 17mUI RMS
 TJ : 276mUI p-p

	real	imaginary	ANn
a[0]	-2.2129e-01	3.2488e+00	-1.9221
a[1]	-5.0368e-06	-1.5261e-05	-3.1415
a[2]	-5.2032e-11	1.8501e-10	-2.3304
a[4]	-7.2995e-21	-7.4721e-21	-1.6857

$$IL_{TP2}(f) = 20 * (A_0 + A_1(f)^{1/2} + A_2(f) + A_4(f)^2) / \log(10)$$

*Note: There is 0.88 instrumentation loss that should be calibrated out.

Equalized and Raw data from Channel 1



Benefits Over TWDP

- TP2 specifications only rely on measured TP2 channel with exception of propagated noise.
- Tied directly to the SDD21 loss budget
- Assumes nothing about the Rx other than what KR assumed.
- Assumes nothing about the Tx except what KR assumed.

TP2 to TP5 Noise Propagation

Table 85.yyy

Equations to propagate noise

short channel

$$\text{loss} = 39e-6 * \sqrt{f} + 300e-12 * f \quad 85-x1$$

long channel

$$\text{loss} = 154e-6 * \sqrt{f} + 1200e-12 * f \quad 85-x2$$

tap	long channel	short channel
0	0.0240	-0.0673
1	0.0071	0.2062
2	0.3299	0.7307
3	0.2710	-0.0223
4	0.0805	0.0729
5	0.0746	-0.0205
6	0.0300	0.0359
7	0.0378	-0.0151
8	0.0159	0.0235
9	0.0239	-0.0118
10	0.0099	0.0173
11	0.0170	-0.0097
12	0.0068	0.0137
13	0.0129	-0.0082
14	0.0049	0.0113
15	0.0103	-0.0071
16	0.0037	0.0096
17	0.0085	-0.0063
18	0.0029	0.0084
19	0.0072	-0.0057
20	0.0023	0.0074
21	0.0062	-0.0051
22	0.0019	0.0066
23	0.0054	-0.0047
24	0.0016	0.0060
25	0.0048	-0.0043
26	0.0013	0.0055
27	0.0043	-0.0040
28	0.0011	0.0050
29	0.0039	-0.0037